Issue C	Classification

Application/Control No.	Applicant(s)/Patent under Reexamination
10/709,762	HSIEH, WEI-JIA
Examiner	Art Unit

2653

					IS	SUE CLASS	SIFICA	ATION				
ORIGINAL						CROSS REFERENCE(S)						
CLASS SUBCLASS CLASS				SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)						
720 646			646									
11	NTER	TERNATIONAL CLASSIFICATION										
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Matthew Kayrish 1/10/2006 (Assistant Examiner) (Date)						WILLIAM KORZUCH SUPERVISORY PATENT EXAMINER				Total Claims Allowed: 6		
(Legal Instruments Examiner) (Date)						TECHNOLOGY CENTER 2800 (Primary Examiner) (Date)				O.G. Print Claim(s)	O.G. Print Fig	
					(Date)					1	1	

Matthew G. Kayrish

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28 58 88 118 148 178	208
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